



Contribution ID: 44

Type: **not specified**

## **Muon- and Neutron-Induced Single-Event Upsets in 65-nm Static Random Access Memories (invited)**

*Thursday, 26 September 2019 10:40 (30 minutes)*

**Presenter:** WATANABE, Yukinobu (Kyushu University)

**Session Classification:** MLF-IN